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An extensive evaluation of the stochastic countdown

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Abstract

The countdown method (CM, Ben-Porath et al., 1989) and its stochastic extension (SC, Finkelman et al., 2012), have been shown to be very cheap but valuable additions to the field of variable-length classification testing, which is dominated by methods based on psychometric models (Thompson, 2007). In this simulation study CM and SC are extensively studied under a series of varying factors such as calibration sample size, number of items, distributional shape of sum scores, location of decision threshold, inter-item correlations and sum score reliability. Preliminary rules for minimal requirements are suggested.

References

Ben-Porath, Y. S., Slutske, W. S., & Butcher, J. N. (1989). A real-data simulation of computerized adaptive administration of the MMPI. Psychological Assessment: A Journal of Consulting and Clinical Psychology, 1(1), 18.

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